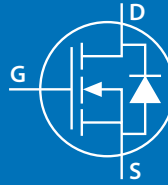


EPC2069 – Enhancement Mode Power Transistor

 $V_{DS}, 40\text{ V}$
 $R_{DS(on)}, 2.25\text{ m}\Omega$
 $I_D, 80\text{ A}$


Revised October 26, 2024

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Questions:
Ask a GaN
Expert



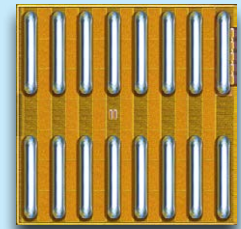
Maximum Ratings			
PARAMETER		VALUE	UNIT
V_{DS}	Drain-to-Source Voltage (Continuous)	40	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	48	
I_D	Continuous ($T_A = 25^\circ\text{C}$)	80	A
	Pulsed (25°C , $T_{PULSE} = 300\text{ }\mu\text{s}$)	422	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	$^\circ\text{C}$
T_{STG}	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.35	$^\circ\text{C/W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.1	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	46	

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0\text{ V}$, $I_D = 0.7\text{ mA}$	40			V
I_{DSS}	Drain-Source Leakage	$V_{GS} = 0\text{ V}$, $V_{DS} = 32\text{ V}$		0.01	0.7	mA
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5\text{ V}$		0.01	4	
	Gate-to-Source Forward Leakage [#]	$V_{GS} = 5\text{ V}$, $T_J = 125^\circ\text{C}$		0.05	9	
	Gate-to-Source Reverse Leakage	$V_{GS} = -4\text{ V}$		0.01	0.8	
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 14\text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5\text{ V}$, $I_D = 30\text{ A}$		1.6	2.25	m Ω
V_{SD}	Source-Drain Forward Voltage [#]	$I_S = 0.5\text{ A}$, $V_{GS} = 0\text{ V}$		1.6		V

[#]Defined by design. Not subject to production test.



Die Size: 3.25 x 3.25 mm

EPC2069 eGaN® FETs are supplied only in passivated die form with solder bars.

Applications

- High frequency DC-DC converters
- BLDC motor drives
- Sync rectification for AC-DC and DC-DC

Benefits

- High power density
- High efficiency
- No reverse recovery
- Ultra low Q_G
- Small footprint
- High frequency capability

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



<https://lead.me/EPC2069>

Dynamic Characteristics[#] ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{ISS}	Input Capacitance	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		1351	2027	pF
C_{RSS}	Reverse Transfer Capacitance			32		
C_{OSS}	Output Capacitance			1044	1566	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }20\text{ V}, V_{GS} = 0\text{ V}$		1465		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			1647		
R_G	Gate Resistance			0.4		Ω
Q_G	Total Gate Charge	$V_{DS} = 20\text{ V}, V_{GS} = 5\text{ V}, I_D = 30\text{ A}$		12.5	16.2	nC
Q_{GS}	Gate-to-Source Charge	$V_{DS} = 20\text{ V}, I_D = 30\text{ A}$		3.9		
Q_{GD}	Gate-to-Drain Charge			2.4		
$Q_{G(TH)}$	Gate Charge at Threshold			2.9		
Q_{OSS}	Output Charge	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		32	48	
Q_{RR}	Source-Drain Recovery Charge			0		

[#]Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

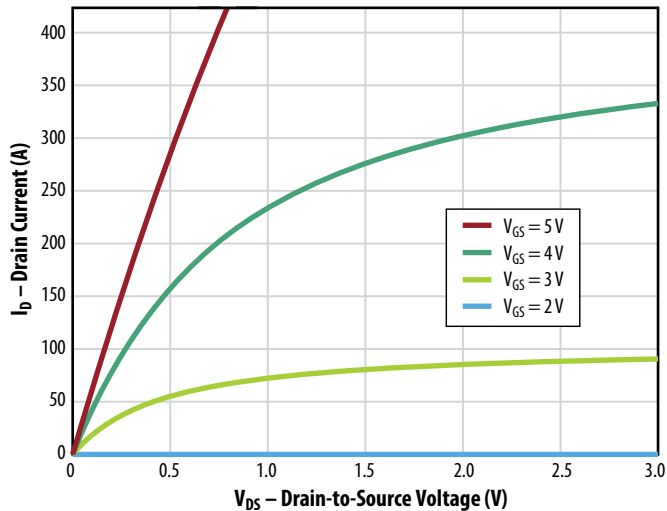
Figure 1: Typical Output Characteristics at 25°C 

Figure 2: Typical Transfer Characteristics

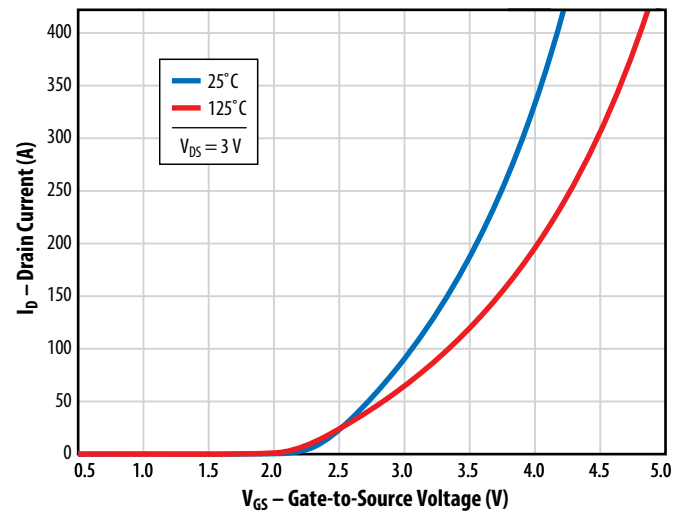
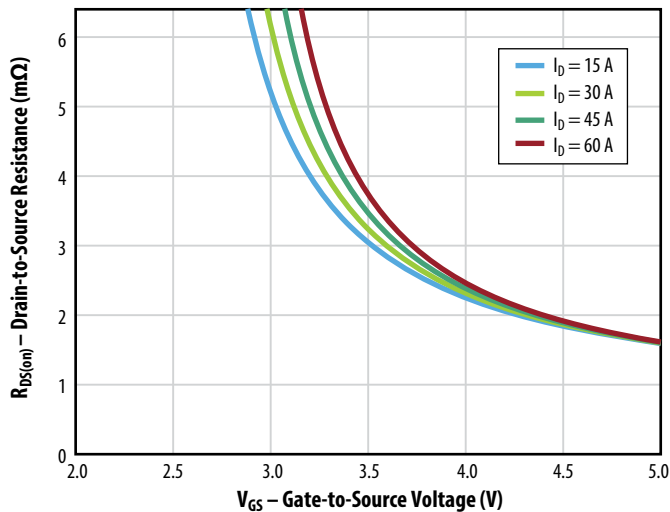
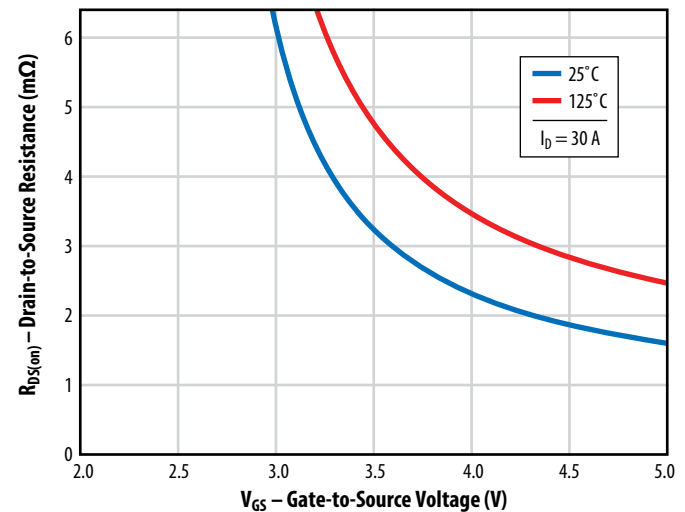
Figure 3: Typical $R_{DS(on)}$ vs. V_{GS} for Various Drain CurrentsFigure 4: Typical $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

Figure 5a: Typical Capacitance (Linear Scale)

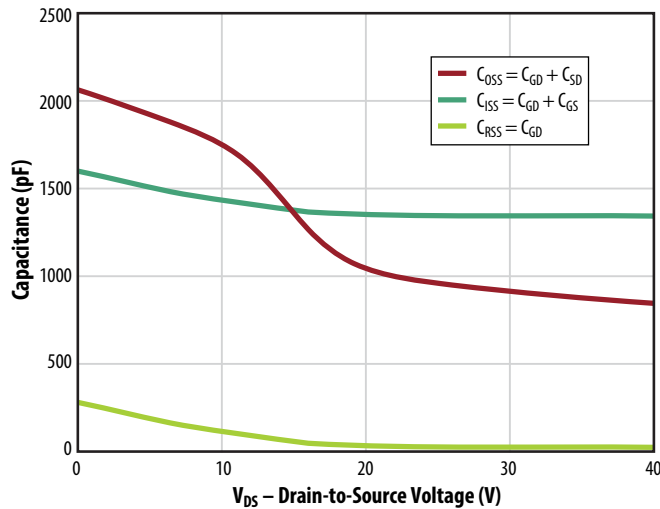


Figure 5b: Typical Capacitance (Log Scale)

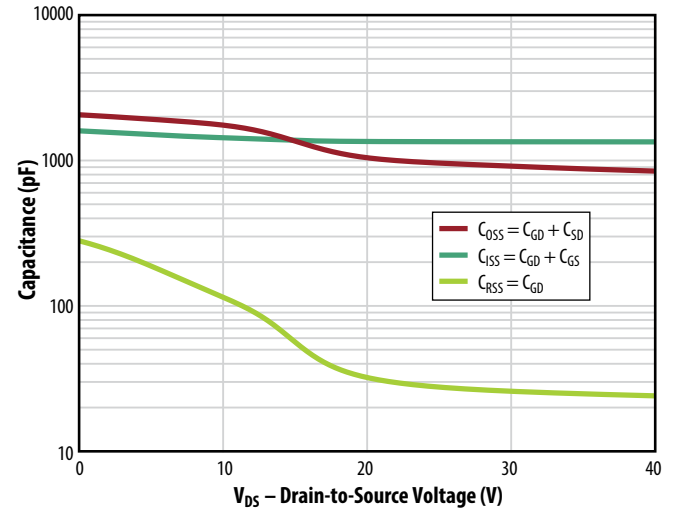
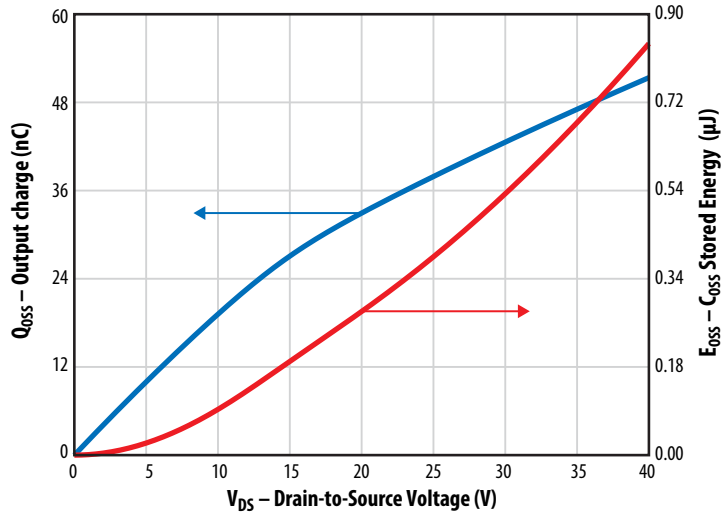
Figure 6: Typical Output Charge and C_{OSS} Stored Energy

Figure 7: Typical Gate Charge

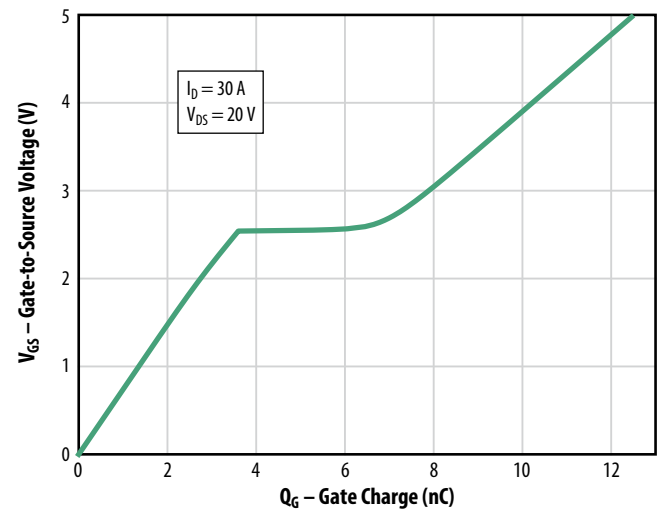


Figure 8: Typical Reverse Drain-Source Characteristics

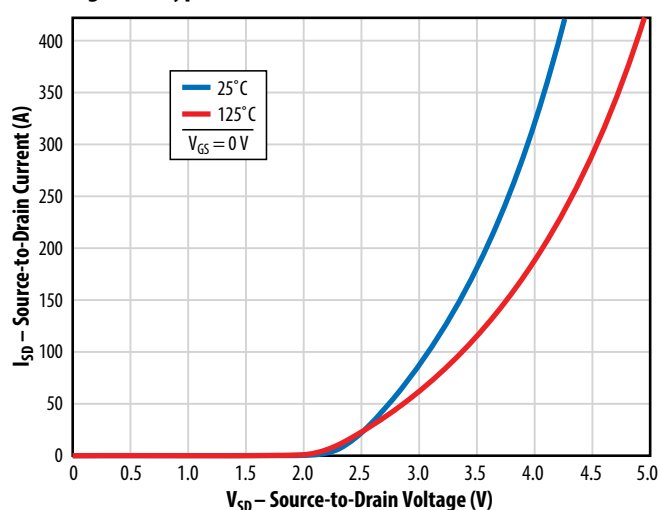
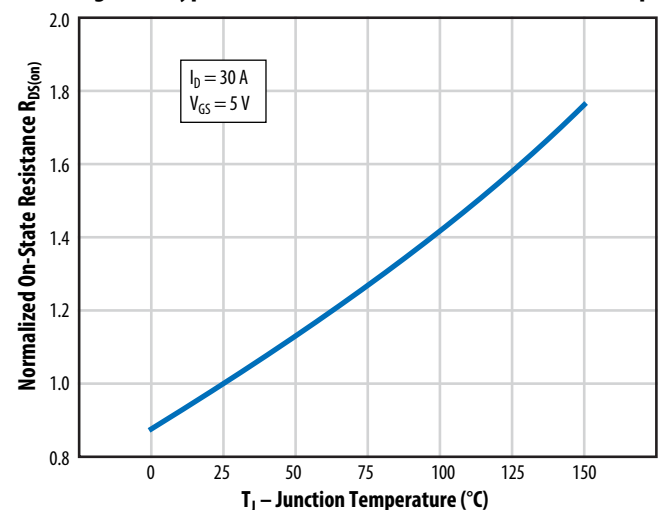


Figure 9: Typical Normalized On-State Resistance vs. Temp.



Note: Negative gate drive voltage increases the reverse drain-source voltage.
EPC recommends 0 V for OFF.

Figure 10: Typical Normalized Threshold Voltage vs. Temperature

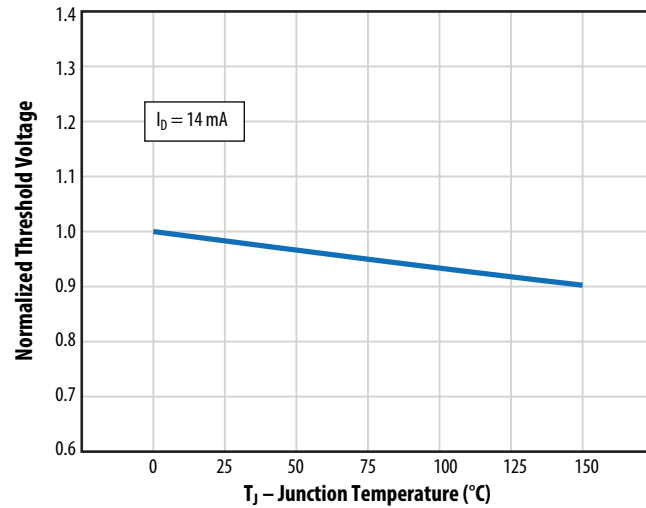


Figure 10: Typical Transient Thermal Response Curves

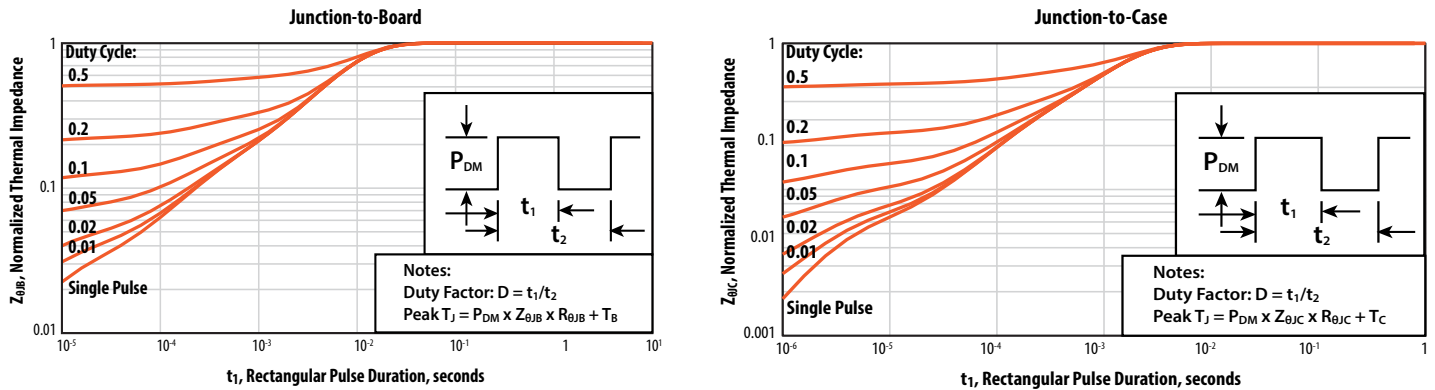
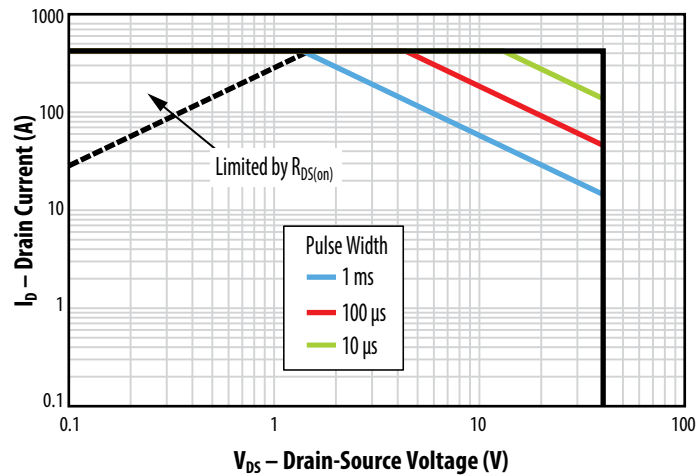
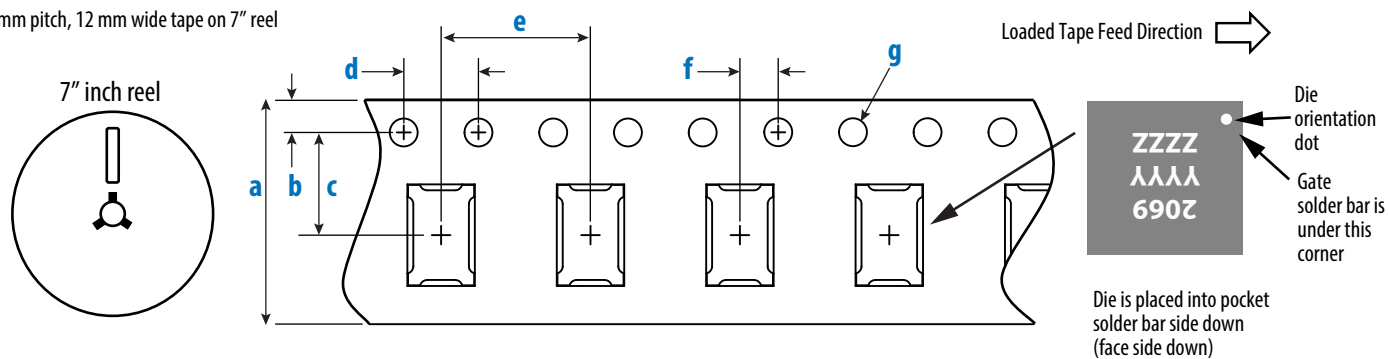


Figure 11: Safe Operating Area



TAPE AND REEL CONFIGURATION

8 mm pitch, 12 mm wide tape on 7" reel

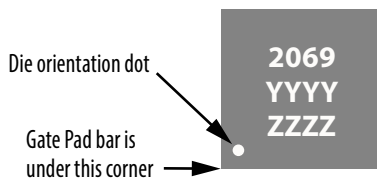


EPC2069 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60

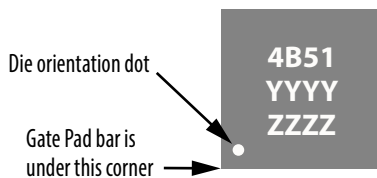
Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

DIE MARKINGS



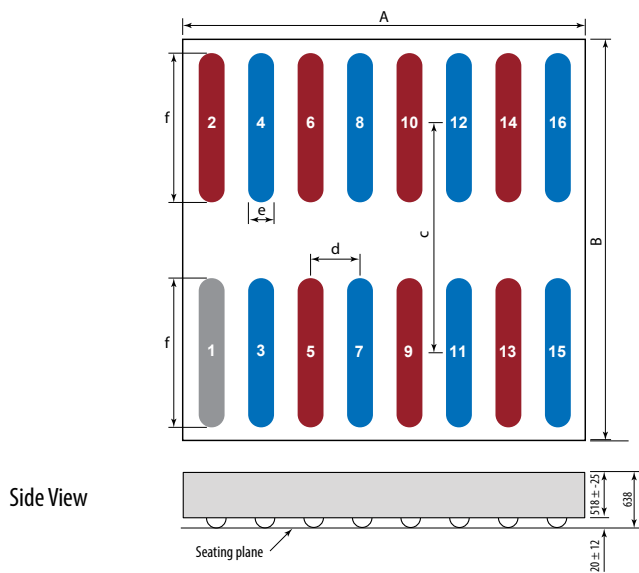
Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2069	2069	YYYY	ZZZZ



Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2069	4B51	YYYY	ZZZZ

DIE OUTLINE

Solder Bump View

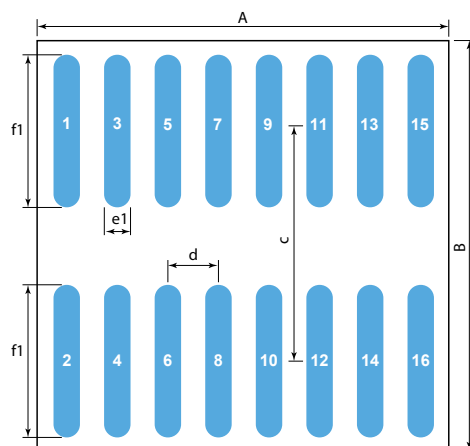


DIM	Micrometers		
	MIN	Nominal	MAX
A	3220	3250	3280
B	3220	3250	3280
c		1805	
d		400	
e	180	200	220
f	1175	1195	1215

Pad 1 is Gate;

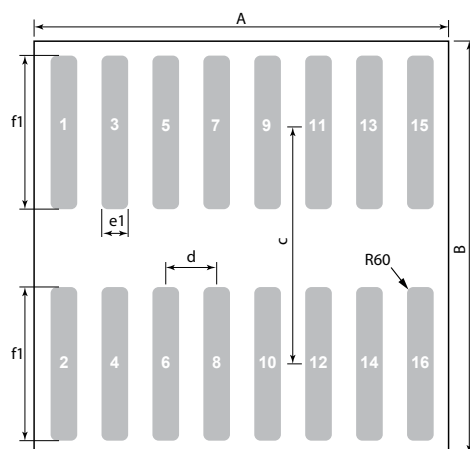
Pads 2,5,6,9,10,13,14 are Source;

Pads 3,4,7,8,11,12,15,16 are Drain

RECOMMENDED LAND PATTERN(units in μm)

Land pattern is solder mask defined

DIM	Micrometers
A	3250
B	3250
c	1805
d	400
e1	180
f1	1175

RECOMMENDED STENCIL DRAWING(units in μm)

DIM	Micrometers
A	3250
B	3250
c	1805
d	400
e1	180
f1	1175

Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, openings per drawing

The corner has a radius of R60

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content

Additional assembly resources available at:

<https://epc-co.com/epc/design-support>

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